


<b>Search Notes</b> 	<b>Application/Control No.</b> 10825575	<b>Applicant(s)/Patent Under Reexamination</b> HEINONEN ET AL.
	<b>Examiner</b> <del>Kowalewski, Filip A</del> Kai Rajan	<b>Art Unit</b> 3736

SEARCHED			
Class	Subclass	Date	Examiner
600	300-301	2/2006	KR
128	903-905	2/2006	KR

SEARCH NOTES		
Search Notes	Date	Examiner
Search updated	2/2006	KR

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner